Analysis of Single Molecule Fluorescence Microscopy Data: a tutorial

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Abstract

The diffraction of light imposes a fundamental limit on the resolution of light microscopes. This limit can be circumvented by creating and exploiting independent behaviors of the sample at length scales below the diffraction limit. In super-resolution microscopy, the independence arises from individual fluorescent labels switching between dark and fluorescent states, which allows the pinpointing of fluorophores either directly during the experiment or post experimentally using a sequence of acquired sparse image frames. Finally, the resulting list of fluorophore coordinates is utilized to produce high resolution images or to gain quantitative insight into the underlying biological structures. Therefore, image processing and post-processing are essential stages of super-resolution microscopy techniques. Here, we review the latest progress on super-resolution microscopy data processing and post-processing.

1 Introduction

Some ancient Greeks believed that vision was due to light rays originating from the eye and traveling with infinite speed. Ibn al-Haytham, latinized as Alhazen (965 AD-1040 AD) explained that eyesight was due to light which comes to the eyes from objects. He also described the optical properties of convex glasses in his \textit{Book of Optics} \cite{1}. The works of Alhazen were introduced to European scholars such as Roger Bacon (1219 AD-1292 AD) via Latin translations. The use of convex lenses as eye-glasses dates back as far as the 13th century in Europe. Telescopes and microscopes came into existence in the 17th century and credit is often given to the Dutch scientists Zacharias Janssen (1585 AD-1638 AD) and Hans Lippershey (1570 AD-1619 AD) \cite{2}. Robert Hooke (1635 AD-1703 AD) was the first person that wrote a book on microscopes, \textit{Micrographia}, and was the first person to see a cell through a microscope \cite{3}.

1.1 Limits of Light Microscopy

The diffraction of light emitted by a point source and collected by a microscope lens (objective) has an intensity pattern called the Airy disk. In general, the actual pattern may differ from the Airy disk due to optical aberrations, etc., and is referred to as a point spread function (PSF). The resolution of a microscope is often defined as the minimum separation between two emitters in which they can still be recognized as individual point sources of light by the microscope user. In 1873, Ernst Abbe defined resolution as the inverse of the maximum spatial frequency passed by the microscope, which
gives a resolution distance of \[d = \frac{\lambda}{2N_a}\] (1)

where \(\lambda\) and \(N_a\) are, respectively, the wavelength of light and the numerical aperture of the microscope (\(N_a = n \sin \theta\), where \(n\) is the refractive index of the medium and \(\theta\) is the maximum angle of the light rays that can be collected by the microscope). For visible light, \(\lambda \sim 600\) nm, and for a typical objective, \(N_a \sim 1.5\), so the resolution is approximately 200 nm. Other significant limiting factors of light microscopy are that only strongly refractive objects can be imaged effectively, the objective lens only collects a small portion of light/information from the sample, and the contribution of unwanted out of focus light from parts of the specimen outside the focal plane.

In the beginning of 20th century, the realization of fluorescence microscopy was a major breakthrough in the examination of living organisms since these organisms are mostly transparent and only reflect a very small portion of light [5]. The advent of fluorescence microscopy was an important step in overcoming the substantial limit of weak refractivity of the sample. Illumination and optical techniques, such as the confocal microscope [6], total internal reflection fluorescence (TIRF) microscope [7], two-photon microscopy [8], 4-pi microscope [9], structured illumination microscopy (SIM) [10], and light-sheet microscopy [11] were developed to reduce the out of focus light and enhance the resolution and contrast of microscope images. These techniques pushed the Abbe diffraction barrier to its very limits, however, it was not until the end of 20th century that scientists were able to overcome this barrier and achieve resolutions better than the diffraction limit [12].

2 Wide-field, Point Scanning and Light-sheet Microscopy

The microscopy techniques listed in the previous section can be divided into three main categories, wide-field microscopy, point scanning microscopy and light-sheet microscopy. In the wide-field approach, the entire specimen is exposed to a light source and therefore there is fluorescent light from out-of-focus points/planes, which obscures the underlying structure and reduces the image contrast. Point scanning microscopes only illuminate a single spot of the sample at a time and use pinholes embedded in the optical setup to considerably reduce the out-of-focus light. In light-sheet microscopy, the focal plane is illuminated rather than the focal point.

2.1 Wide-field Microscopy

Total Internal Reflection Microscopy. In TIRF microscopy, a beam of light is incident upon the coverslip at an angle greater than the critical angle of the coverslip, Fig. 1a. At this angle, light undergoes a total internal reflection and is entirely reflected back from the coverslip. However, an exponentially decaying electromagnetic wave called the evanescent wave penetrates the sample with intensity

\[I = I_0 e^{-z/d}\] (2)

where \(z, I_0\) and \(d\) are, respectively, depth, the intensity of the evanescent wave at \(z = 0\), and the effective depth that the evanescent wave travels within the specimen. \(d\) is of the order of the wavelength, \(d \sim \lambda\), and fluorophores further than \(d\) from the coverslip will not be effectively activated and therefore result in an extensive reduction of the out-of-focus light. This approach is simple to implement and is usually suitable for imaging structures close to the coverslip, \(z \sim 0\), such as the cell membrane [7][13]. TIRF microscopy is a wide-field approach, but it provides better contrast due to the small penetration of the evanescent wave into the sample, described by (2), and therefore less out-of-focus light.
Structured Illumination Microscopy. One of the barriers of light microscopy is the limited size of the objective, which prevents collection of all the light/information available from the sample. The numerical aperture in the denominator of (1) is related to the ability of the objective in collecting light/information. Structured illumination microscopy (SIM) collects more information by illuminating the sample with a periodic field instead of a uniform field.

A sinusoidal periodic field is usually used in a SIM experiment which has a Fourier transform with three different spatial frequencies. The fact that a sinusoidal field is represented by more than one frequency component in the Fourier domain adds complications to the actual problem. However, for the sake of explanation, we presume that one can generate a field with a single spatial frequency and employ it for a SIM experiment.
Assuming that \( f(x) \) describes the sample with Fourier transform

\[
F(k) = \int f(x) e^{-ikx} dx,
\]

the product of \( f(x) \) with \( e^{-ik_0x} \), which stands for a periodic field with spatial frequency \( k_0 \), leads to a shift in the frequency domain:

\[
F(k + k_0) = \int f(x) e^{-ik_0x} e^{-ikx} dx
\]

Taking advantage of this simple math, one can make more information available through the objective lens by shifting the frequency plane illuminating the sample by using fields with different spatial frequencies, Fig. 2.

Images acquired by different illumination fields are then combined to obtain an image with enhanced resolution. SIM provides a resolution of \( \sim 100 \) nm in the lateral direction [10, 14]. Note that this is still not breaking the diffraction limit, but SIM permits reconstruction of images with higher spatial frequencies than allowed by \( N_a \), which pushes the diffraction barrier to its very limits.

Figure 2: Structure illumination microscopy. (a) The frequencies of the modulated fields used for illumination. ‘*’ shows convolution. (b) Original monkey image. (c) The Fourier transform of the monkey in (b). The objective is only able to collect the frequencies inside the green circle. (d) The reconstruction of the monkey employing the frequencies inside the circle. (e) The area within the green curve contains the frequencies collected making use of the structure illumination. (f) The monkey reconstruction using the frequencies within the green curve in (e).
2.2 Point Scanning Microscopy

**Confocal Microscopy.** In the wide-field illumination approach, the entire sample is exposed to a beam of light and out-of-focus fluorophores are activated as well as in-focus fluorophores. The light from the out-of-focus fluorophores interferes with the light from in-focus structures and results in blurry details of in-focus structures. A confocal microscope uses two pinhole apertures after the light source and before the camera to reduce the out-of-focus light, Fig. 1b. A single spot of the sample is illuminated at each time and the specimen is scanned point-by-point to obtain an image of the entire sample with improved contrast due to the reduction of out-of-focus fluorescence background.

**4-pi Microscopy.** 4-pi microscopy was initially developed as a variant of confocal microscopes, Fig. 1c. Similar to SIM, 4-pi microscopy permits collection of more light which yields a larger numerical aperture, giving a better resolution. Due to isotropic light collection, 4-pi microscopy yields an almost symmetric PSF in all directions and hence is of special interest in 3D microscopy.

**2-photon and Multi-photon Microscopy.** Certain fluorophores can be activated by absorbing two or more photons at the same time. Due to the superposition of the fields from the photons arriving at the focal point simultaneously, the resulting focal point has a smaller size. Therefore, the out-of-focus fluorophores are less likely to be activated, which reduces the out-of-focus fluorescent light. In this approach, the specimen is scanned point by point to acquire an image of the whole sample with enhanced contrast.

2.3 Light-sheet Microscopy

In light-sheet microscopy, a thin sheet of laser beam is generated and used to illuminate the in-focus plane and then a wide-field light collection approach is used to collect the fluorescent light from the fluorophores within the focal plane. The illumination and light collection are in perpendicular directions, Fig. 1d. Two common approaches to generate a thin layer of light are using a cylindrical lens or rapid movement of the focal point across a plane. Because the out-of-focus fluorophores are not illuminated, the out-of-focus light is at a minimum and also photo-damaging is less for the fluorophores. This approach has been widely adopted for 3D-imaging of samples by imaging one plane of the sample at a time.

3 Super-resolution Microscopy

Fluorescence microscopy techniques along with various illumination and light collection methods pushed the diffraction limit to its extreme. For example, TIRF microscopy, confocal microscopy, 2-photon microscopy, and light-sheet microscopy were developed using different illumination techniques to eliminate spurious fluorescent light from out-of-focus fluorophores. SIM and 4-pi microscopy employ light collection techniques to gather more information from the emitted fluorescent light to increase the numerical aperture and obtain better resolutions. However, these techniques do not break the diffraction limit resolution and the resolution still depends on the size of the PSF. The microscopy approaches that break the diffraction limit barrier are called super-resolution microscopy or nanoscopy. Super-resolution techniques achieve sub-diffraction resolution by creating independent behavior for individual dyes at scales below the diffraction limit. Many super-resolution procedures use the reversible switching property of some fluorescent probes between a fluorescent state.
and a dark state to obtain sub-diffraction limit resolution. These approaches can be classified into two different groups based on how they switch the probes between the dark and fluorescent states: targeted switching procedures and stochastic switching procedures. The microscopy techniques under the first category are STimulated Emission Depletion (STED) microscopy [12, 28], Ground State Depletion (GSD) microscopy [29], REversible Saturable Optically Linear Fluorescence Transition (RSOLFT) microscopy [30] and Saturated Structured Illumination Microscopy (SSIM) [31]. These techniques deterministically switch off the fluorophores in the diffraction limited vicinity of the target fluorophore to accomplish sub-diffraction resolution. Stochastic Optical Reconstruction Microscopy (STORM) [32], direct Stochastic Optical Reconstruction Microscopy (dSTORM) [33], Photoactivated Localization Microscopy (PALM) [34], Fluorescence Photoactivation Localization Microscopy (FPALM) [35], Super-resolution Optical Fluctuation Imaging (SOFI) [36] and DNA-Point Accumulation for Imaging in Nanoscale Topography (DNA-PAINT) [37, 38] can be categorized as stochastic switching techniques. These approaches activate a small random subset of the probes to avoid simultaneous fluorescent light from more than one probe in a diffraction limited region.

3.1 Targeted Switching Super-resolution Microscopy

**Stimulated Emission Depletion Microscopy.** In STED, the specimen is simultaneously illuminated by two sources of light. The first source of light is used to excite the fluorophores and the second one restricts the fluorescent emission [12]. When a fluorophore in an excited state encounters a photon with the same energy as the difference between the excited state and ground state, it can emit a photon and return to the ground state via stimulated emission. The beam profile of the second laser has a donut-like shape where the intensity of light is almost zero in the middle and the chance for stimulated emission is very small. Therefore, fluorophores in the surrounding region will be depleted and fluorescent emission only occurs in the middle. The resolution is given by the size of the middle area with zero intensity. The diameter of this region (resolution) is given by

\[
d = \frac{\lambda}{2N_a \sqrt{1 + I_s/I}}
\]

where \(I\) and \(I_s\) are the intensity of the laser used for suppressing the spontaneous fluorescent emission and the saturation intensity. The stimulated emission depletion of the exited state has to compete with the fluorescence decay of this state, and the fluorescence decay is overcome at the saturation intensity, \(I_s\). Higher laser power gives a smaller hole in the center of the donut-like laser profile and thus better resolution. This technique bypasses the diffraction limit and achieves resolution of 20-50 nm [41-43]. Advantages of STED are computational post-processing is not required, and two channel imaging is easy to implement [44]. Disadvantages of this technique are long image acquisition time and high power lasers, such as pulsed lasers.

**Ground State Depletion Microscopy.** GSD is another approach that makes use of patterned excitation to achieve sub-diffraction resolution [29]. Fluorophores have singlet and triplet spin excited states with spins of zero and one, in turn [45, 46]. In this technique, a triplet spin state is employed as the dark state rather than the ground state, Fig. 3.

A first laser excites the fluorophores to the singlet state, \(S_1\). A second laser is then utilized to pump the electrons from \(S_1\) to the triplet state \(T_1\) outside the region of interest (ROI). The lifetime of the triplet state, \(T_1\), is much longer than that of the singlet state, \(S_1\), because transition from the triplet state to the ground state, \(S_0\), with spin zero is prohibited by angular momentum conservation. Therefore, the electrons in the triplet state do not emit fluorescent light. GSD requires lower intensity for depletion and has a smaller threshold intensity \(I_s\) [5] than STED [17]. This super-resolution scheme has yielded resolutions better than 20 nm [48].
Figure 3: Energy levels in a fluorophore. The ground state, $S_0$, and the excited state, $S_1$, are singlet spin states. $T_1$ is a triplet spin state, which has a long lifetime and is used as a dark state in GSD.

**Reversible Saturable Optically Linear Fluorescence Transition Microscopy.** RESOLFT is a more general approach that uses any fluorophore with a dark state and a bright state with reversible switching between the two states to accomplish super-resolution [30]. STED and GSD are specific cases of RESOLFT where the ground state, $S_0$, and the triplet state, $T_1$, are the bright and dark states, respectively, Fig. 3.

**Saturated Structured Illumination Microscopy.** SSIM uses a high power laser with a sinusoidal spatial pattern to deplete the ground state of fluorophores. The generated pattern has very narrow line-shaped dark regions with sub-diffraction widths. The dark lines can later be exploited to retrieve features of the sample with sub-diffraction resolution.

### 3.2 Stochastic Switching Super-resolution Microscopy

#### 3.2.1 Single Molecule Localization Microscopy

A high-resolution image of a structure, for example, a cellular organelle, can be reconstructed from fluorophore positions, Fig. 4. This is the foundation of Single Molecule Localization Microscopy (SMLM) super-resolution approaches, such as STORM [32], PALM [34] and FPALM [35], conceived by different groups around the same time, and other variants introduced later [33, 37, 38, 49–57].

A fluorophore in its fluorescent state emits $N$ photons that form a PSF pattern on the camera. The PSF can be used to localize the fluorophore with a localization precision much better than the diffraction limit [58, 59]

$$
\sigma = \frac{\sigma_{PSF}}{\sqrt{N}}
$$

where $\sigma$ and $\sigma_{PSF}$ are the localization precision and size of the PSF, respectively. However, two major deterrents to accurate and precise localizations are overlapping PSFs when multiple fluorophores in close proximity are activated [60, 61], and small photon counts per blinking event, which leads to low signal to noise ratio.

SMLM super-resolution approaches were originally demonstrated by making use of a wide-field illumination method to activate a sparse subset of fluorescent probes that can be stochastically switched between a dark and a fluorescent state. Sparse activation is necessary to prevent activation
of more than one fluorophore in a diffraction limited area and avoid overlapping PSFs [32–35,49–51]. Some other SMLM approaches overcome the problem of overlapping PSFs by separating the fluorescent signals from molecules with different emission spectra [52–54] or lifetimes [62]. Photo-bleaching of fluorophores has also been employed to achieve low density images of PSFs with minimum overlaps [55, 56]. Another promising SMLM technique is based on stochastic binding and unbinding of the diffusing fluorescent emitters to the target, such as DNA-PAINT [57–58,57], and lifeact [63,64].

The sparsity constraint results in a small subset of activated fluorophores and therefore a few localizations per frame. On the other hand enough localizations are required to obtain high-resolution images [65], which demands undesired long data acquisition times [66,67]. This problem can be alleviated by multiple-emitter fitting methods that are able to localize emitters in denser regions of the data [68–70].

For various fluorescent probes, the number of emitted photons per blinking event ranges from a few hundreds to a few thousands with a few blinking events per probe, where more photons and a larger number of blinking events are desired for better localization precision and image contrast [71].

Although wide-field techniques are the most common illumination procedures in SMLM approaches, other illumination methods such as confocal [72], 2-photons [73] and light-sheet [74,75] approaches have been utilized to demonstrate SMLM super-resolution microscopy.

Cellular organelle are inherently 3D structures and therefore 3D microscopy images are desirable. SMLM super-resolution approaches are able to provide 3D images of cellular structures by exploiting the variance in the PSF shape as a function of axial distance from the focal plane. The variance in the PSF shape can be achieved by different optical techniques. STORM was first implemented in 3D by using an astigmatic PSF [76]. Later approaches used more complex engineered PSFs such as double-helix [77], etc. [78–80].

Figure 4: SMLM concept. (a & c) Sample frames of raw super-resolution data. (b) Image reconstructed using localizations from a single frame. (d) Image reconstructed using localizations from 50 frames. (e) Bright-field image, which is the sum image of 5000 frames of raw super-resolution data. (f) Super-resolution image reconstructed using localizations from 5000 frames.
3.2.2 Fluctuation Analysis

Super-resolution Optical Fluctuation Imaging (SOFI) is another technique that utilizes stochastic switching of fluorophores to realize sub-diffraction details of cellular structures. However, this approach does not reconstruct super-resolution images using probe locations. It employs temporal fluctuation analysis methods to generate images with resolution beyond the diffraction limit [36,81,82]. More recently, Super-Resolution Radial Fluctuations (SRRF) has been introduced that takes advantage of radial and temporal fluctuations in the fluorescent intensity to realize sub-diffraction information from the sample [83,84].

4 Image Formation

Raw super-resolution data is comprised of a sequence of image frames, where each frame is a two-dimensional array of pixels whose values are a function of the number of photons captured by the camera over a fixed exposure time. Photons reaching the camera are often originated from multiple sources of light: the fluorescent light from in-focus fluorophores that label the target structure, the fluorescent light from out of focus fluorophores which might be fluorophores bound to undesired cellular structures, and the autofluorescence of the specimen or other sources of light that exist in the area. The contribution of the light from sources other than the in focus fluorophores is unwanted and degrades the quality of images [65,85]. The undesired light reaching the camera gives rise to two types of background noise, an approximately uniform, homogeneous background, and a heterogeneous background called structured background [85–88].

For each data frame, a subset of emitters is activated and the image frame is described by

\[
\text{Model} = \sum_i I_i \delta(x - x_i) \delta(y - y_i) \ast \text{PSF}(z_i) + b, \tag{7}
\]

which is the convolution of the emitter X and Y locations with the PSF plus a uniform background, Fig. 5. The sum is over the activated emitters. \( I_i, x_i, y_i, z_i \) and \( \delta \) represent the intensity and location of the \( i \)th emitter and Dirac delta, respectively. Note that PSF shape is a function of the Z-location (offset from the focal plane) of the emitter [86,89], and hence the out-of-focus emitters have a different PSF. Some effects like dipole orientation [90,91], sample movements [92,93] and optical aberrations [91,94] also result in distortions of the PSF. The additive term models the homogeneous uniform background, while the structured background, usually coming from the out-of-focus emitters, is mixed with the in-focus emitters and is given by the convolution term.

The pixel values recorded by the camera are not the same as the photon counts, but they are a function of photon counts. The camera detectors amplify the signal from the detected photons and multiple photoelectrons are produced per photon, which is used to generate the pixel values [95]. The detector also has Gaussian fluctuations when there is no signal, which is called read-out-noise. To obtain the correct number of photons, therefore, these two effects have to be taken into account [96,99]. The pixel values are scaled by the camera gain, which gives the amplification factor, and the average of the camera offset is subtracted from the given pixel values to get photon counts, where the Gaussian fluctuations are negligible in most cases [96,97]. Another major source of noise is shot noise, which comes from the particle nature of photons and can be modeled by a Poisson process [59,96,100,101]. Model (7) yields the expected number of photons for individual pixels, but the number of photons captured by the detector over a fixed exposure time have a Poisson distribution, Fig. 5.
Figure 5: Image Formation. (a) Emitter locations. (b) Model is a convolution of emitter locations with the PSF. (c) Model corrupted with shot (Poisson) noise. The emitters are assumed to be in focus.

5 Image Processing

Image processing is a key step in SMLM super-resolution approaches. This step is comprised of multiple stages: pre-processing, identification of candidate emitters, and localization, filtering and image rendering. The pre-processing step often alleviates the noise introduced during data acquisition, such as camera and background noise.

Estimation of location and/or intensity of emitters using the point spread function predates the advent of SMLM super-resolution approaches and had been employed in other scientific disciplines such as electrical engineering [102–104], astronomy [87, 100, 105, 106], particle tracking [107, 108], etc. There are two major classes of localization approaches, single-emitter localization algorithms and multiple-emitter localization algorithms. The single-emitter algorithms are only able to localize isolated emitters where there is no overlapping PSFs. Single-emitter candidates are usually identified by applying a threshold to detect local maxima and then ROIs of a certain size including those local maxima are selected for further analysis [58,101,109,110]. Other common detection algorithms employ wavelet transform [111–113], different types of filters [60,114] and other detection approaches [115,116]. The performance of different detection algorithms is highly correlated with the signal to noise ratio (SNR) and signal to background ratio. For a comparison of different detection algorithms, see [117,118]. The single-emitter localization procedures estimate the locations of the detected emitters employing either a non-iterative or an iterative algorithm.

Dense regions of data with overlapping PSFs from closely spaced activated emitters, Fig. 5, can be generated due to either dense labeling of the sample or fast data collection. Multiple-emitter fitting algorithms localize emitters in the dense regions of the data with overlapping PSFs. Multiple-emitter approaches may be categorized based on their outputs [68] or based on the algorithm itself [69,70].

After the localization stage, there is often a rejection step that filters out bad localizations to reduce the artifacts in the final reconstructions [119,120]. A popular filtering criteria is based on the found parameter values and their uncertainties that removes the localizations with uncertainties larger than given thresholds [32,88,119]. An additional filtering approach is based on the nearest neighbor distances where localizations with less than $N$ neighbors within a certain distance are eliminated from the final list of localizations [121,122].

In single-emitter localization approaches, artifacts may arise due to fitting two or more overlapping PSFs as a single emitter. To reduce this effect, the localization algorithms make use of different criteria for recognizing this type of bad fits, Fig. 6. The filtering of the ROIs, including closely spaced active emitters with overlapping PSFs, can be done before localization. The ROIs with overlapping PSFs are identified by a deviation in shape of the bright blob from the given PSF [32]. Another algorithm recognizes the bad fits due to overlapping PSFs by computing the p-value assuming a single PSF as the null hypothesis. If the resulting p-values are smaller than a given threshold, the
fits are rejected [101]. Finally, the remaining localizations are used to reconstruct a super-resolved image, Fig. 6.

5.1 Background Detection

The ultimate objective of SMLM techniques is reconstructing high resolution images from precise and accurate [86] estimates of the emitter locations from raw super-resolution data. In order to accomplish this goal, a correct measure of background noise is required as incorrect background leads to biased position estimates [68]. The correction of uniform background noise is simple, and various approaches have been conceived to address this issue. These approaches usually select a ROI and use that to compute a local uniform background noise as the average of pixel values, median of pixel values, average of pixel values after bleaching of the fluorophores, Xth percentile of pixel values or estimating the additive term in (7) using an iterative approach [89,101,123–126].

Structured background is significantly more complicated to remove and its presence results in poor position estimates. A few methods have been put forward to cope with this problem including an approach that uses a temporal median filter to subtract structured background from the signal [127]. This technique inspects the fluctuations of pixel values over time to find the background value. The found background can be overestimated in the dense regions of the data where there is at least one active emitter at each time. An alternative procedure detects all the emitters regardless of being signal or background and then sets a threshold and remove the emitters with intensities below that as structured background [128]. Wavelet decomposition has been employed to subtract structured background as well as uniform background, prior to emitter detection [129]. Recently, a deep learning method has been proposed to detect structured background using the PSF shape [85]. Fazel, et al. used a Bayesian approach to model structured background with a collection of PSF-sized dim emitters [88]. In the field of astronomy, methods such as sigma clipping had been developed to deal with structured background in dense data sets [87]. In the sigma clipping procedure, the brightness mean, \( m \), and standard deviation, \( \sigma \), are calculated and those intensities outside the range of \([m - \alpha\sigma, m + \alpha\sigma]\) are considered noise [87].

5.2 Single Emitter Fitting

The single-emitter localization algorithms can be classified into two major categories: the algorithms that use non-iterative approaches to localize emitters and the algorithms that use an iterative procedure. Studies show that the iterative algorithms are more accurate than the non-iterative algorithms [130]. However, iterative algorithms are computationally more demanding and require a precise PSF model.

5.2.1 Non-iterative Algorithms

Non-iterative algorithms do not need any information about the PSF and are usually fast and easy to implement. However, they are not as accurate as iterative algorithms that utilize the PSF to generate a model of the data. The lack of enough accuracy is often a consequence of different types of noise.

A few non-iterative approaches such as QuickPALM [131] calculate the emitter locations as center of mass of ROIs containing single emitters [77,131]. This gives a good estimation of location, however, failure in background correction results in biased localizations towards the center of the ROIs. Virtual Window Center of Mass (VWCM) [132] ameliorates this issue by iteratively adjusting the selected ROI to minimize the separation of the emitter location and the center of the ROI.

FluoroBancroft borrows the Bancroft procedure from the satellite Global Positioning System (GPS) to localize emitters [111,133]. This approach uses three pixel values within a PSF to draw three circles where the emitter is located within the intersection of these three circles. The size of
the intersection region is a measure of the localization precision. A correct measure of background is also of great importance in this approach to calculate accurate radii.

Single emitters can also be localized by finding the gradient of the phase of the Fourier transform of ROIs. For a single emitter, equation (7) reduces to

\[ I(m, n) = I_0 \delta(x - x_0) \delta(y - y_0) \ast \text{PSF}(z_0) + b(m, n) \quad (8) \]

where \( m \) and \( n \) count rows and columns of pixels in the ROI, and \( x \) and \( y \) give the centers of those pixels. The Fourier transform of intensity in pixel \( k \) and \( l \) is given by

\[ \tilde{I}(k, l) = H(k, l) \exp \left[ -i2\pi \left( \frac{x_0}{M} k + \frac{y_0}{N} l \right) \right] + \tilde{b}(k, l) \quad (9) \]

where \( M \) and \( N \) are the two array dimensions and \( H \) is a real function. For data sets with large SNR, the background term is negligible and Fourier Domain Localization Algorithm (FDLA) gives the emitter position by the average of the gradient of the phase \[ x_0 = \frac{\text{mean} \left( \left( \frac{\partial \phi}{\partial k} \right) \right) M}{2\pi}, \quad y_0 = \frac{\text{mean} \left( \left( \frac{\partial \phi}{\partial l} \right) \right) N}{2\pi} \]

(10) where \( \phi = \arctan \frac{\text{Im}(\tilde{I})}{\text{Re}(\tilde{I})} \). The performance of this approach suffers from the presence of background noise as well. Another approach localizes single emitters by calculating the first Fourier coefficients in both X and Y directions, and the phase of these coefficients are then employed to find the emitter location \[ x_0 = \frac{\text{mean} \left( \left( \frac{\partial \phi}{\partial k} \right) \right) M}{2\pi}, \quad y_0 = \frac{\text{mean} \left( \left( \frac{\partial \phi}{\partial l} \right) \right) N}{2\pi} \]

(10)

Radial symmetry of the PSF has also been employed to calculate emitter locations \[ x_0 = \frac{\text{mean} \left( \left( \frac{\partial \phi}{\partial k} \right) \right) M}{2\pi}, \quad y_0 = \frac{\text{mean} \left( \left( \frac{\partial \phi}{\partial l} \right) \right) N}{2\pi} \]

(10)

Due to the radial symmetry of PSFs, intensity gradient vectors for different pixels converges to the region with maximum intensity where the emitter is located. This approach is robust in the presence of uniform background noise and achieves precision close to the Cramer Rao Lower Bound (CRLB).

### 5.2.2 Iterative Algorithms

Iterative algorithms are the most rigorous approaches for emitter localization. In these approaches, the parameters in model (8) are adjusted in an iterative manner to fulfill a certain criterion. In the localization problem, the parameters are \( (x_0, y_0, z_0, I_0, b) \), the emitter location, the number of photons from (intensity of) the emitter and a uniform background noise. The criteria that are extensively utilized in the emitter fitting literature are the Least Square (LS) difference between data and model and maximizing the likelihood function via a Maximum Likelihood Estimate (MLE).

Cramer Raw Lower Bound (CRLB) states that the fundamental limit of variance for estimating a parameter from given data is given by the inverse of the Fisher Information \[ \text{MLE achieves the best localization precision, equivalent to CRLB} \]

Theoretically, MLE achieves the best localization precision, equivalent to CRLB \[ \text{LS performance is comparable to the MLE under certain conditions described below} \]

The performance of weighted LS approaches that of MLE at high signal to noise ratio, when the Poisson noise (shot noise) can be well approximated by a Gaussian model, or when read-out noise is dominant. Note that neither of these scenarios are correct for super-resolution data where the read-out noise is usually negligible in the presence of Poisson noise and the SNR is not too high. In general, MLE yields better localization accuracy and is more robust in the presence of PSF mismatch, but is computationally more complex and requires an accurate model of noise \[ \text{Least Squares Fitting. The least-squares approaches iteratively vary the parameters of the model to minimize the sum of differences between the pixel values from the data and the model. This} \]

12
difference is given by

\[ D = \sum_{\text{pixel}} \frac{(\text{data} - \text{model})^2}{\text{expected variance}} \quad (11) \]

where in weighted LS the differences are scaled by the expected variance of the noise which scales the errors for individual pixels \([77][94][143][146]\). A pixel with a high signal is expected to have a large noise variance and therefore it is allowed to have a larger error in the weighted LS procedure. However, the scaling factor is replaced by one in the unweighted LS algorithm, which we call LS hereafter, and does not accommodate noises \([58][77][94][145][146]\). The developed algorithms use the Gaussian PSF \([58][94]\), theoretical PSFs \([145][146]\) or experimentally acquired PSFs \([143][148]\) to make a model of the data. The Levenberg-Marquardt iterative procedure \([145][148][149]\) or other procedures \([143]\) are then employed to iteratively adjust the parameters of the model.

The weighted least square algorithms accomplish accuracies close to the CRLB when the photon count is high, but the noise variance needs to be known as well as an accurate PSF model. The PSF mismatch, particularly in the tail of the PSF, results in large errors when scaled by a small expected noise variance in the pixels far from the emitter \([68]\). Therefore, the unweighted least square algorithm is more suitable when a reasonable PSF model and/or noise model are not accessible.

**Maximum Likelihood Estimator.** The photons from a point-like emitter have an approximate spatial Gaussian distribution \([60][94][101][109][144][150][151]\) on the camera which can be employed to calculate the photon counts for different pixels eq. \((12)\). In cases where the Gaussian PSF is not an appropriate approximation, theoretical PSF models \([101][139][152]\) can be used or numerical PSFs can be obtained from calibration experiments \([153][156]\). The array of PSF samples is then utilized to generate a likelihood model of the ROI via either linear or cubic spline interpolation approaches \([154][156]\).

Using the Gaussian approximation for a PSF, the photon count is given by

\[
\Delta_k = \frac{I_0}{2\pi\sigma_{\text{PSF}}(z_0)} \int_{x_k-0.5}^{x_k+0.5} \int_{y_k-0.5}^{y_k+0.5} \exp \left[ \frac{(x-x_0)^2 + (y-y_0)^2}{2\sigma_{\text{PSF}}(z_0)^2} \right] dx \, dy \quad (12)
\]

where \(\Delta_k, \sigma_{\text{PSF}}, I_0, x_0, y_0, z_0, x_k\) and \(y_k\) are, respectively, the number of photons in the \(k\)th pixel from the emitter, the half width of the Gaussian PSF, total number of photons from the emitter, the emitter location and the center of the \(k\)th pixel.

The total photon count in the \(k\)th pixel is the sum of the photons from the emitter and the uniform background noise

\[ \lambda_k = \Delta_k + b \quad (13) \]

Equation \((13)\) yields the expected number of photons for pixel \(k\) for a fixed exposure time. Consequently, the number of detected photons in pixel \(k\) has a Poisson distribution, which gives the likelihood of the \(k\)th pixel

\[ P_k(D|\theta) = \frac{\lambda_k^{D_k} e^{-\lambda_k}}{D_k!} \quad (14) \]

where \(\theta\) stands for the set of parameters \((\theta = (x_0, y_0, I_0, b))\). \(D\) represents data, which is a two dimensional array of pixels whose values are related to the number of photons detected by the camera. \(D_k\) selects the \(k\)th pixel in \(D\). Since the pixels are independent, the likelihood of the ROI can be written as the product of the likelihoods of all the pixels in the ROI.

\[ P(D|\theta) = \prod_k P_k(D|\theta) \quad (15) \]

The two main iterative algorithms employed in the literature to find the parameters that optimize the above likelihood are variations of the Newton method \([94][101][150][152][154][155]\) and a modified version of Levenberg-Marquardt \([60][144][156][157]\) adopted from LS procedures.
The Newton approach is employed to find the root of the derivative of the likelihood function \(^{15}\), and therefore one needs to calculate the second derivative of the likelihood as well, which is computationally demanding. On the other hand, the Levenberg-Marquardt algorithm only calculates the first derivative of the likelihood, which makes it computationally less demanding in comparison \(^{14, 156}\). Different strategies have been exploited to speed up the Newton optimization algorithm including implementation on Graphical Processing Units (GPUs), which allows parallel analysis of ROIs \(^{101, 109, 150, 151, 155}\); starting from better initial values \(^{139}\); and estimating X and Y positions individually utilizing the separability property of the Gaussian function \(^{151}\).

5.3 Multiple Emitter Fitting

Raw SMLM super-resolution data is often acquired via a wide-field illumination procedure and the whole sample is exposed to the excitation laser. Emitter activation is a stochastic process and hence there will always be activated emitters at close proximity. Therefore, overlapping PSFs are unavoidable, even under sparse activation conditions. The overlapping PSFs are eliminated in a filtering step in single-emitter approaches, which results in losing information \(^{138}\), as well as the appearance of artifacts, for instance, contrast inversion, Fig. 6.
Figure 6: Reconstructions from dense data with overlapping PSFs. (a) A frame of dense raw super-resolution data of a cross with parallel lines. The green circle shows an example of two overlapping PSFs. (b) Reconstruction from multiple-emitter algorithm with no filtering. (c) Reconstruction from single-emitter algorithm with no filtering. The localizations in the area between the lines are the results of fitting overlapping PSFs with a single PSF. (d) Reconstruction from single-emitter algorithm after filtering. The dense regions of data appear sparse when processed with a single-emitter algorithm due to the inability to localize overlapping PSFs, which is called the contrast inversion artifact.

The inability of single-emitter algorithms to localize activated emitters in a diffraction limited vicinity enforces the sparse activation of emitters. This is followed by a long acquisition time to build a full list of localizations to reconstruct an image with high resolution. In some experiments, such as studies of live or dynamic samples, fast data acquisition is preferred and hence dense activation of emitters is inevitable. Therefore, proper analysis of dense super-resolution data with overlapping PSFs is necessary to reduce data acquisition time, avoid artifacts, facilitate live sample imaging, etc.

Numerous multiple-emitter fitting algorithms have been devised to fit emitters with overlapping PSFs, some borrowed from other areas, such as astronomy, statistical analysis, etc. The reported
algorithms employ a very wide range of approaches and have a broad spectrum of performance [69, 70]. These procedures are often iterative algorithms or include an iterative training step.

5.3.1 Least Squares

The LS algorithm has been employed to fit multiple-emitters in the field of astronomy [87]. It was modified for SMLM super-resolution microscopy, called DAOSTORM in this context [158]. DAOSTORM uses isolated emitters in the raw data to estimate the PSF and then uses the found PSF to fit emitters in dense data sets. The algorithm starts with an initial number of emitters located at the brightest pixels of the ROI, and then uses least squares fitting to localize them with sub-diffraction precision. Next, the residuum image is calculated by subtracting the model from the data, and is used to detect new emitters in the pixels brighter than a given threshold. The detected emitters are then localized to obtain subdiffraction precision. This step is repeated until there is no pixel with intensity above the threshold in the residuum image.

5.3.2 Maximum Likelihood

The MLE approach that was described before can be modified for multiple-emitter fitting within ROIs with overlapping PSFs. The total photon counts in the kth pixel is given by

\[
\lambda_k(N) = b + \sum_{i=1}^{N} \Delta_{k,i}
\]  

(16)

where \(\Delta_{k,i}\) is the number of photons received in the kth pixel from the ith emitter and can be calculated using (12). \(N\) and \(b\) are the number of emitters and the uniform background. The likelihood of the pixel is then given by

\[
P_k(D|\theta) = \frac{\lambda_k(N)^{D_k} e^{-\lambda_k(N)}}{D_k!}
\]  

(17)

The likelihood of the ROI is obtained from the product of the likelihoods of individual pixels (15).

The likelihood (17) has more than one emitter and therefore more parameters to estimate, demanding more iterations and computational time. The MLE approach is implemented in the same manner as single-emitter fitting to estimate the parameters. Nevertheless, there is a new parameter, \(N\), the number of emitters, which cannot be directly estimated from the likelihood itself. The approaches that find the number of emitters are called model selection algorithms. Several model selection algorithms have been reported along with the MLE localization procedure, including thresholding of the residuum image [159], p-value of the likelihood ratios [138], Bayesian Information Criteria (BIC) [160, 161], PSF size and nearest neighbor distance [162] and others [163–165].

The 3D-DAOSTORM [159] is a 3D multiple emitter fitting approach. 3D fitting procedures will be discussed in the next section and here we explain how this procedure deal with overlapping PSFs. 3D-DAOSTORM fits overlapping PSFs by fitting only choices from the brightest emitters in the ROI at the beginning. It then subtracts the obtained model from the ROI intensities and uses the residuum image to find pixels brighter than a given threshold to detect new emitters. It employs MLE to localize the new emitters. The new emitters are added to the list of detected emitters and this step is repeated until there is no pixel brighter than a given value.

Simultaneous multiple-emitter fitting [138] starts from one emitter, \(N = 1\), and goes up to \(N = N_{max}\). For each model, this method localizes the emitters employing the MLE approach. The log-likelihood ratio (LLR)

\[
LLR = -2 \log \left[ \frac{P(D|\hat{\theta})}{P(D|\theta)} \right]
\]  

(18)
has an approximate chi-square distribution \[138\], where \( \hat{\theta} \) is the parameters that maximize the likelihood and \( P(D|\hat{\theta}) \) gives the upper limit of the likelihood. The model with lowest \( N \) that meets a threshold \( p \)-value is accepted as the best fit.

The MLE approach suffers from overfitting, and adding more parameters (emitters) tends to give larger values for likelihoods. Bayesian Information Criteria is a model selection algorithm that penalizes adding new parameters to an MLE problem. SSM-BIC \[160\] selects the model that maximizes the following function

\[
\text{BIC}(N) = \frac{(\text{Data} - \text{Model})^2}{\text{Data}} + (3N + 1) \log (m)
\]  

(19)

where \( m \) is the number of pixels in the given ROI. Note that there are \( 3N + 1 \) parameters in a model with \( N \) emitters. This approach has also been implemented on GPUs with \( \sim100 \) times faster computational time \[161\].

QC-STORM \[162\] uses a weighted likelihood \( P_{W}(D|\theta) = \prod_{k} W_{k} P_{k}(D|\theta) \) (20) to localize emitters, where \( W_{k} \) is the weight of the \( k \)th pixel and is smaller for pixels closer to the edges of the ROI. The weighted likelihood suppresses the signal close to the edges of the ROI and it is therefore an effective method to localize emitters within ROIs with signal contaminations close to their edges. QC-STORM identifies ROIs with more than one emitter based on the ROIs’ nearest neighbor distances and the size of the PSF estimated using weighted MLE. This algorithm has been implemented on GPUs and is capable of processing very large fields of view.

Some other approaches use an iterative deconvolution algorithm to accomplish maximum likelihood employing the Richardson and Lucy procedure \[166, 167\]. These approaches return a grid image with finer pixel sizes than the camera pixel size with non-zero pixel values at the emitter locations rather than returning a list of localizations.

5.3.3 Bayesian Inference

The MLE algorithm suffers from overfitting as discussed above. Bayes’ formula \[21\] provides an elegant way to include prior knowledge into the problem, allowing the problem to be restricted to reasonable number of parameters. It however adds complications to the problem by including more distributions. It has been shown that the Bayesian approach can achieve localization uncertainties better than those from MLE by inclusion of reasonable prior knowledge \[168\]. The Bayesian paradigm is equivalent to MLE when there is no prior knowledge available. The posterior is given by

\[
P(\theta|D) = \frac{P(D|\theta)P(\theta)}{P(D)}
\]  

(21)

called the evidence. Another difference of MLE and Bayesian approaches is that MLE returns fixed emitter parameters (location and intensity), while the Bayesian procedure returns a probability distribution, the posterior, for the emitter parameters. A few fully Bayesian algorithms have been developed for multiple-emitter fitting so far \[88,169,170\], where we discuss two of them here.

The Bayesian multiple-emitter fitting (BAMF) algorithm \[88\] employs the Reversible jump Markov chain Monte Carlo (RJMCMC) \[171,172\] technique to explore model spaces with different dimensions or equivalently different number of emitters, and returns a posterior distribution.
which is a weighted average of different possible models. BAMF uses either a Gaussian PSF model
or an arbitrary input numerical PSF along with an empirical prior on emitter intensities to attain
precise and accurate localizations in dense regions of data. This technique performs emitter fit-
ting, model selection and structured background modeling simultaneously and therefore takes into
account various sources of uncertainties which are often ignored.

The 3B algorithm \[169\] analyzes the entire data set at the same time by integrating over all
possible positions and blinking events of emitters. This algorithm makes inference about the emitter
locations, intensities, width of the Gaussian PSF and blinking of emitters. The posterior of this
problem is given by

\[ P(a, b, M | D) = \frac{P(D | a, b, M) P(a)}{P(D)} \]  \hspace{1cm} (23)

where \(a, b\) and \(M\) represent the emitter parameters, blinking events and the number of emitters,
in turn. 3B uses a uniform prior for the locations and a log-normal prior for other parameters.
The discrete parameter, \(b\), is then integrated out using an MCMC \[173\] approach to obtain the
posterior distribution of \(a\), \(P(a, M | D)\). Next, the Maximum A Posteriori (MAP) is computed using
the conjugate gradient approach to obtain the emitter locations, intensities and PSF sizes. After
that, the parameter \(a\) is also marginalized to get the model probability, \(P(M | D)\), for model selection.

The 3B algorithm models the entire data set and is able to use all the collected photons from
multiple blinking events to achieve better localization precision. The returned image is a probabil-
ity map of the weighted average of all possible models rather than a selected single model \[174\].
Moreover, it needs a simple experimental setup for data collection \[169\]. However, it is reported
that 3B suffers from artificial thinning and thickening of the target structures \[169\]. This technique
is very slow because calculating the integrals to marginalize parameters \(a\) and \(b\) is extremely com-
putationally demanding. There have been several attempts to speed up the algorithm including 3B
implementation in cloud computing \[175\], use of more informative priors \[176\], and initializing the
algorithm with better starting parameter values \[177\].

5.3.4 Compressed Sensing

A frame of super-resolution data can be considered as a matrix \(y\)

\[ y = Ax + b \]  \hspace{1cm} (24)

where \(x\) is the signal, which is an up-sampled discrete grid (image) with non-zero elements at the
emitter locations, \(A\) is the PSF matrix and \(b\) is the uniform background. The objective is to recover
the non-zero elements of the signal \(x\) where most of the elements are zero due to sparse activation
of fluorescent emitters in SMLM microscopy. Compressed Sensing (CS) theory states that a signal
\(x\) can be recovered from a noisy measurement \(y\) if the signal is sufficiently sparse \[178\]. This
mathematically can be expressed as

\[
\text{Minimize : } ||x||_1 \\
\text{Subject to : } ||y - (Ax + b)||_2 \leq \epsilon
\]  \hspace{1cm} (25)

where \(||x||_1 = \sum_i |x_i|\) is the L1-norm of the up-sampled image, and the L2-norm of the residuum
image is given by

\[ ||y - (Ax + b)||_2 = \sqrt{\sum_i (y_i - (Ax + b)_i)^2} \]  \hspace{1cm} (26)

The inequality allows fluctuations from the expected model due to different types of noise.

Various mathematical approaches have been utilized to minimize the L1-norm in the presence
of the given restriction in \(25\) including the convex optimum algorithm \[179\], L1-Hotomopy \[180\],
gradient descent \[129\] and others \[181, 182\]. These algorithms are able to detect and localize the
emitters in very dense regions of the data. However, due to the large size of the up-sampled image, the CS algorithms are slow and the resolution cannot be better than the grid size of the up-sampled image.

The issues mentioned above have been addressed in later literature using different approaches. FALCON [129] accelerates the algorithm by implementing CS on GPUs. It ameliorates the grid-size problem by refining the found locations in the subsequent steps after the deconvolution stage. CS has recently been implemented over continuous parameter spaces to remove the limits imposed by the up-sampled grid [183,184]. To lower the computational cost of the CS algorithm, a recent paper models the entire sequence at the same time rather than employing a frame by frame analysis of the data [185]. Another approach implements the CS algorithm in the correlation domain by calculating the frame cross-correlations [186].

**Singular Value Decomposition**

Assuming $A$ as a $n \times n$ square matrix with non-zero determinant, it can be factorized into

$$A = U \Sigma U^{-1}$$

where $U$ is a $n \times n$ matrix whose columns are the eigenvectors of decomposition and $\Sigma$ is a diagonal $n \times n$ matrix where the diagonal elements are the eigenvalues. A non-square matrix $B$ can also be decomposed in a similar fashion, called the singular value decomposition (SVD)

$$B_{n \times m} = V_{n \times n} \Lambda_{n \times m} W_{m \times m}$$

where $V$ and $W$ are, respectively, $n \times n$ and $m \times m$ matrices. $\Lambda$ is a diagonal $n \times m$ matrix with diagonal elements the eigenvalues of $B$ [187].

The MUltiple SIgnal Classification ALgorithm (MUSICAL) for super-resolution fluorescence microscopy [188] takes $B$ as a collection of frames of super-resolution images where each column of $B$ is a frame of the raw data. $B$ is then a non-square matrix that can be factorized into a diagonal matrix and unitary matrices where the eigenvectors are eigenimages. The eigenimages are next classified into signal and noise based on their eigenvalues using a given threshold. Finally, MUSICAL calculates the projection of the PSF at different locations in the eigenimages to identify and localize the emitters. An alternative method makes use of the SVD in the Fourier domain, analyzing the sequence of raw data frame by frame to localize the emitters [189].

**Deep Learning**

Deep learning approaches are non-iterative optimization algorithms that perform calculations in a parallel manner and hence are very fast. These approaches are based on Artificial Neural Networks (ANN) that are inspired by animal brains and neural systems. The building blocks of the brain are neurons equivalent to perceptrons or sigmoid neurons in ANNs [190]. Perceptrons take a few binary inputs and generates a binary output, Fig. 7.

The output of the perceptron is one if the sum of inputs times their weights is larger than a threshold and is zero otherwise, eq. [29].

$$\text{Output} = \begin{cases} 0 & \text{if } \sum_i w_i \text{ input}_i < \text{threshold} \\ 1 & \text{if } \sum_i w_i \text{ input}_i > \text{threshold} \end{cases}$$
It can be shown that certain combinations of perceptrons produce logical operations such as AND, OR and NAND, which are the underlying bases of computation and any mathematical function could be generated using them [190]. Therefore, ANNs are capable of producing any mathematical function using perceptrons. A network of perceptrons can be trained to perform different tasks by adjusting the weights, \( w_i \). Sigmoid neurons are more sophisticated versions of perceptrons where the output is a value within the interval of [0, 1] rather than a binary output. Sigmoid neurons are more flexible in the training process and are used in neural networks.

ANNs have been employed to attack various problems in the field of biomedical imaging [191, 192], specifically for SMLM image processing [193]. Convolutional Neural Networks (CNNs) have been employed for super-resolution image processing. CCNs consist of two stages. The first stage of the network receives the input image and then encodes the information into a smaller number of pixels via multiple layers of neurons. This step averages out insignificant details and helps with denoising. Next, the encoded information in the first step is decoded and upsampled to a super-resolved image with a finer pixel size than the input image [191].

CNNs designed to localize emitters in super-resolution raw data can be categorized into three different types based on their training approach:

1) ANNs are trained using simulated data where the ground truth is available or using localizations found using a standard iterative algorithm [194–196]. In the training stage, the ANN learns by minimizing the sum of distances between the found localizations and the given locations. Using synthesized data, there will always be adequate training data.

2) ANNs are also trained using two well-registered sets of data acquired from the same sample where one of them is used as ground truth. The ground truth image has high SNR that can be acquired employing different procedures such as confocal microscopy [197, 198], using an objective with high numerical aperture [199], or using a sparse data set to reconstruct a super-resolved image with high SNR [200] to train the network. In the training stage, the network learns by minimizing the difference between the output image and the acquired image with high SNR. The minimization of differences can be implemented via a standard iterative optimization algorithm [197] or by using a sub-network in the training stage called a discriminative network [199, 200]. The discriminative network takes the output of the CNN along with the ground truth images and labels the output as real or fake.

3) In an alternative training approach, there is no additional inputs for the training step and the network is trained by reproducing the input data from the list of found emitters and minimizing the difference between the original input and the synthesized image [201]. This training procedure is called unsupervised learning.

The deep learning procedures are very fast during the analysis. There are no required input parameters or thresholds, and their performance is comparable to the MLE algorithm [196, 202]. However, the training process is very sensitive and has to be done very carefully. Some pitfalls of training are the hallucination problem, the generalization problem, etc. [191]. Deep learning algorithms might make mistakes in identifying patterns from random inputs when there is not adequate training, which is called the hallucination problem. If there are new patterns that are not
seen by the algorithm before it fits these new data by the old patterns, this is called the generalization problem.

Others

WindStorm [203] uses a temporal filter to estimate the background and remove it from the raw data. It then implements deconvolution by dividing the Fourier transform of the clean image with the Fourier transform of the PSF. It next performs frequency truncation. The recovered locations are given by the peaks of the deconvolved image in the spatial domain. This is a fast and non-iterative approach and the found locations can be used as initial values for iterative algorithms.

Wedge Template Matching (WTM) [204] identifies and localizes emitters by matching an entire or partial template of the PSF to the regions of the data with overlapping emitters. The WTM algorithm picks either an entire or partial PSF template based on the degree of overlapping between PSFs. It finds the candidate pixels containing emitters using cross correlation of the template with the image, and then finds the locations of the detected emitters with sub-pixel accuracies.

Other approaches employ machine learning algorithms [205], independent component analysis and a shape matching approach in the frequency domain [206], and other algorithms [207] to identify and localize emitters in dense regions of the data.

5.4 3D fitting

Biological samples are 3D in nature and 3D microscopy approaches are required to gain better insight into biological structures. A standard super-resolution microscope cannot provide precise axial location of an emitter due to slow changes in the 3D PSF as a function of axial position \((z)\) [142]. Super-resolution microscopes can however provide precise axial location of an emitter by some alterations in the optical setup. Several different modifications have been reported in the literature encompassing multi-focal methods [143, 147, 208, 209] which image multiple focal planes at the same time; engineered PSFs [76, 80, 210, 211] where the axial information is encoded into the PSF shape; and other procedures [212, 215].

The multi-focal approaches allow precise axial emitter localization by providing multiple \(z\)-slices of the PSF. The PSF engineering approaches attains precise axial localization of emitters by inscribing axial information in the shape of the PSF by simple phase front modifications. The modification in phase front can be achieved by inserting extra optical components [76, 78, 216] or computer controlled phase modulators [77, 79, 211, 217] in the optical path. Several engineered PSFs have been devised for 3D super-resolution microscopy including an astigmatic PSF [76], double-helix PSF [77], phase ramp PSF [78], corkscrew PSF [210], self bending PSF [211], and tetrapad PSF [79, 217]. These PSFs have special characteristics, such as relative motions of different parts, width variations in different directions, etc. that quickly changes as a function of axial location. The engineered PSFs cover different ranges of axial locations. The tetrapad PSF was designed to accomplish precise lateral emitter locations over the largest axial range compared to the other PSFs [70, 79, 142].

Most of the 2D emitter fitting algorithms discussed in the previous sections can be adapted for 3D emitter fitting [70, 218]. These approaches employ either a theoretical 3D PSF [76, 101, 108, 184, 219] or an experimentally acquired numeric PSF to calculate the model [131, 147, 153, 156, 222, 228]. More complicated PSFs such as tetrapad or double-helix have very intricate features that cannot be exactly expressed by an analytical function, so the PSF is generated using empirical data from calibration experiments.

The PSF at a \(z\)-plane is given by [154]

\[
PSF(x, y, z) = \int \int P(k_x, k_y) e^{2\pi i(k_x x + k_y y + k_z (k_x, k_y) z)} dk_x \, dk_y \tag{30}
\]

where \(P(k_x, k_y)\) is the pupil function or phase front at the back focal plane, and is a characteristic of the optical setup plus the extra phase added for PSF engineering. Moreover, \(k_x^2 + k_y^2 + k_z^2 = n^2/\lambda^2\)
where \( n \) and \( \lambda \) are, respectively, the refractive index of medium and the wavelength of the wavelength of light in vacuum.

The camera records the intensity values, while the phase information is mostly lost, however there are different approaches that can be employed for phase retrieval from a stack of intensity images acquired at different axial positions, such as the Gerchberg-Saxton algorithm \[154, 229, 230\] and the MLE approach \[165\]. Substituting the obtained phase front in (30), one is able to obtain the PSF at any given location. However, the integral (30) is computationally expensive and therefore the PSF model is generated at just a few \( z \) -slices. The PSF at a desired location can then be numerically produced via either linear or spline interpolation \[154, 156\]. Deep learning approaches have also been recently employed for 3D emitter fitting by training ANNs with PSFs at different axial locations \[196, 201, 202, 231, 232\].

### 5.5 Drift Correction

Drift is a common problem in super-resolution microscopy procedures, in which the sample alters its location overtime, resulting in distortion and degradation in the quality of final images. SMLM microscopy reconstructs high-quality images from a list of localizations collected over the course of an experiment, where even slight disturbances in the experiment lead to serious defects in the results. For instance, mechanical vibrations of the microscope stage or fluctuations in temperature result in rotational or translational movements of the sample during data acquisition. Since such disturbances are unavoidable, algorithms are required to measure and correct for drift in the image processing step.

Multiple drift correction algorithms have been employed in super-resolution microscopy, such as use of fixed fiducial markers during the experiment \[33, 233-238\], image cross-correlation between frames at different times \[239-246\], computing drift directly from the list of found emitter-coordinates \[247-250\] and other procedures \[251-253\].

Fiducial markers are fixed point sources of light or structures during data acquisition that are used as reference points for drift correction. Since fiducial markers are fixed, their movements can be measured in the localization step and used to eliminate drift errors. Fiducial markers can introduce light corruption to the sample and some fiducial markers emit photons for a limited time, which restricts the data acquisition time. Cross-correlation approaches are the most common procedure for removal of drift error and different variants have been reported in the literature. Image noise deteriorates performance of the cross-correlation approaches to calculate drift errors. One algorithm maximizes the cross-correlation of the first frame with the rest of the sequence to calculate drift \[241, 244\]. A fast implementation of cross-correlation is achieved in the Fourier domain \[242, 243, 246\], and some other approaches employ the cross-correlation of the sum images to reduce the effect of noise \[240, 245\]. Some approaches have been developed using the list of found localizations to estimate sample drifts, such as the nearest neighbor distribution of locations \[240, 250\].

Wester, et al. \[250\] made use of a combination of the image registration approach and nearest neighbor distribution of localizations to measure drift in the sample. The algorithm employs periodic 3D registration of the sample using brightfield images to remove drift errors. However, brightfield registration is only accurate to around 10 nm and there might be still residual drift remaining. This approach thus uses post-processing of the localizations to extract residual drift from the nearest neighbor distribution of emitter coordinates. This procedure is robust and also capable of calculating axial drift.

### 5.6 Fitting Quality and Image Quality

The quality of a fit is defined as how close the recovered location of an emitter is to its true location. The fitting quality depends on the emitter detection, emitter fitting and thresholding algorithms. Each of these steps were discussed in previous sections. There are a few metrics to assess the
fitting quality including the Jaccard index (JAC), root mean square errors (RMSE) or accuracy, precision [69, 70], a vectorial model for localization uncertainties [254], and a fit confidence test that examines the stability of a localization by exploring the model in the vicinity of the maximum likelihood [255].

Image resolution is often used as a reporter of image quality. However, there is no widely accepted definition for resolution in super-resolution microscopy literature [86, 141, 256]. There are however a few common metrics that are used to assess microscopy image resolution such as the Abbe/Rayleigh resolution criteria, localization precision [86], signal to noise ratio (SNR), and Fourier ring correlation (FRC) [65].

Fitting Quality

The uncertainty in the location of an isolated emitter is characterized by precision and accuracy. Assuming that an emitter with location \( x_e \) blinks multiple times, there are then multiple found locations, \( x_f \), for the emitter, where each localization corresponds to a blinking event. The found locations are slightly different and spread over a small region around the emitter location, \( x_e \), for a perfect fitting algorithm. The localization precision, \( \sigma_x \), is the standard deviation of the distribution of \( x_f \). This is a fundamental limit for localization precision imposed by the random nature of photons and is not a result of instrument imperfections or flaws in the experiment design [58, 59, 86]. Due to the random nature of photons, each time that the emitter turns on, the number of photons reaching a certain pixel deviates by a small amount, which is called shot noise, resulting in a small deviation in the found location of the emitter, Fig. 8. The fundamental limit of precision for a perfect localization algorithm is given by the square root of the inverse of the diagonal elements of the Fisher information matrix

\[
\sigma_\theta = \frac{1}{\sqrt{N \int_{-\infty}^{+\infty} \frac{1}{L(D|\theta)} \left( \frac{\partial L(D|\theta)}{\partial \theta} \right)^2 d\theta}}
\]  

(31)

Figure 8: Precision and accuracy concepts. Blue dots are the true emitter position and the orange dots stand for found locations. (a) Distribution of the found locations from a perfect fitting algorithm. Precision is proportional to the size of the distribution of the found locations. (b) Distribution of the found locations from a biased fitting algorithm. Accuracy is described as the deviation of the center of the distribution of found locations from the true position.
where \( L(D|\theta) \) is the likelihood given in (14), \( \theta \) and \( N \) stand for the collection of all the parameters and the number of photons, respectively. The fundamental limit of localization precision for lateral coordinates due to shot noise is given by (6). The localization precision in the axial direction is usually worse mainly due to larger size of the PSF out of the focal plane which results in a lower SNR.

Accuracy describes the deviation of the average of the found locations from the true emitter location, Fig. 8. Unlike localization precision, localization accuracy does not have a fundamental limit and can be zero [86]. However, due to instrument imperfections, optical aberrations, etc., the resultant localizations are often a little biased [257, 260]. A set of acceptable localizations of an emitter have similar spreads of precisions and accuracies.

In practice, it is often challenging to achieve unbiased localizations and localization precisions close to the square root of the CRLB variance derived from a too simplistic model that only takes into account the Poisson noise. This is due to other existing factors in super-resolution experiments such as limitations in fitting algorithms, equipment and experiment, such as cameras, PSF mismatch, drift, background noise, etc.

**Camera.** Several properties of cameras, such as camera noise, pixelation, etc., affect the localization precision and accuracy. A major source of noise in cameras is read-out-noise that can affect localization uncertainty. Read-out-noise is particularly important in sCMOS cameras where each pixel has a unique amount of read-out-noise [95, 97]. Model (14) only takes into account shot-noise and ignores the read-out-noise. This model is suitable for EMCCD cameras where the read-out-noise is negligible in comparison to the homogeneous background and has an approximately uniform value over the field of view. However, since read-out-noise has a unique value in each pixel for sCMOS cameras, this can result in degradation in the localization uncertainty. Read-out-noise can be modeled by an additional source of light in sCMOS cameras to improve the localization uncertainty [97, 261].

Scientific cameras are not able to record the exact location of photons reaching them. However, they report the number of photons reached on a region within a certain area called a pixel. This causes loss of accurate locations of photons from an isolated emitter and therefore results in localization uncertainty. This effect is called pixelation. Moreover, sensitivity of cameras can be nonuniform over the field of view, which is another potential source of deterioration of localization precision [86].

**PSF mismatch.** Error-free PSF input to the iterative approaches is of key importance for accurate and precise emitter localization [91]. There are several factors that lead to major deviations between the expected PSF and the resultant PSF, including dipole orientation, emitter motions, changes in the optical properties of the environment like the refractive index, etc. [68, 86, 94, 139, 260, 262]. Fluorophore emitters are electric dipoles in nature and do not emit photons in an isotropic manner, despite the assumption of spatial uniform distribution of photons. A rigid emitter therefore has a nonuniform photon distribution which degrades the fitting quality when using an isotropic approximation of the PSF [90, 91, 263]. However, these emitters usually are free to rotate randomly which provides an isotropic distribution of photons. Emitter movements exist in some experiments due to the nature of samples, like live cell imaging or particle tracking, or due to bad fixation of the sample. This can result in an smearing pattern in the PSF, specifically for large exposure times, when the emitter emits photons while moving [92, 93]. Imaging cellular structures within their native environment often requires light traveling through thick tissues of the specimen. The optical properties of the sample, such as refractive index, changes as a function of location which leads to phase front disturbance of light and therefore distortion of the PSF [260, 262].

**Background.** Another limiting factor for precision and accuracy in localization microscopy is the background noise. Failure in correct background estimation can lead to biased localization estimates as was discussed extensively above. The homogeneous background is usually modeled by an additive offset to the intensity [13]. The situation is worse in the presence of inhomogeneous
background which is more difficult to model and can give rise to more uncertainty in localizations.

**Fitting algorithm.** The limits of the fitting algorithm itself is also an important factor in localization uncertainty. For example, a crude peak finder algorithm that finds the pixels with the maximum intensities has an accuracy comparable to the pixel size. Better localization precision and accuracy come with more computationally expensive algorithms, such as iterative fitting procedures. It was shown that the MLE approach attains the localization precisions comparable to CRLB in the absence of other limiting factors [59,139].

Theoretical calculation of localization precision considering all the important factors is a difficult task, however statistical and experimental techniques have been proposed to calculate localization uncertainties taking into account all those factors [121,264,265]. An approach has been proposed that prescribes a simple way to compute localization precision from nearest neighbor distribution (NND) distances of found localizations [121]. Lee, et al. used well isolated emitters in sparsely labeled biological samples to experimentally measure localization precision under realistic experimental conditions [264].

JAC is a standard metric to measure the quality of fitting for a group of emitters rather than for an isolated emitter [69,70,88]. JAC evaluates the rate of emitter detection versus the density of emitters. This is particularly important for multiple-emitter fitting algorithms which are supposed to detect and localize emitters in dense regions of the data. To perform this test, sets of super-resolution data with different emitter densities are simulated and processed with the given fitting algorithm. Next, the pairs of matching emitters within the sets of found and true locations are found by minimizing the cost metric between the two sets. JAC is calculated as the ratio of the number of matched emitters (ME) to the total number of localizations within both sets

\[
\text{JAC} = \frac{\text{ME}}{\text{FE} + \text{TE}}
\]

where FE and TE refer to the number of found emitters and true emitters, respectively.

**Image Quality**

After conducting an experiment and performing the image analysis, the final result is a super-resolved image reconstructed from list of the found localizations. What a scientist eventually cares about is the quality/resolution of this image and the amount of details that it reveals. The metric to evaluate the two-point resolution of conventional microscopy techniques is Rayleigh's resolution criteria. It can be shown that the Rayleigh two-point resolution criterion is related to localization precision for SMLM super-resolution techniques. Ram, et al. provided an alternative for Rayleigh’s resolution in localization microscopy employing Fisher information theory for two nearby emitters activated simultaneously [266]. Another important factor in evaluating the resolution of reconstructed images in localization microscopy is labeling density [119,267]. To obtain a desired resolution, there should be at least two localized emitters within a distance equal to the desired resolution [86], and the localization precisions must also be smaller than the desired resolution.

Although precision and labeling density are essential parameters in evaluating the resolution of the SMLM reconstructed images, they do not account for all the factors that contribute to deterioration of resolution. For example, resolution also highly depends on the type of structure being examined and differs from experiment to experiment [86,141,268]. For instance, visualization of fine actin filaments requires uniform labeling density as well as high labeling density [63,269], while in imaging nuclear pore complexes (NPCs), the localization precision is of more importance since the sample itself has a discrete structure [270]. Therefore, more advanced theoretical methods for estimation of resolution in localization microscopy have been devised such as the information transfer function (ITF) [271], Fourier ring correlation (FRC) [65,272], super-resolution quantitative image rating and reporting of error locations (SQUIRREL) [273], and algorithmic resolution [274].
Experimental approaches for characterization of resolution have also been reported in the literature, for instance, the use of DNA-rulers, DNA-origami structures or standard biological structures such as NPCs with known spacing between emitters as references to benchmark the ability of microscopy techniques in resolving closely spaced emitters \[270,275,276\]. Some other well characterized biological structures such as microtubules and synthesized raw super-resolution data for different structures such as the Siemens star, crossing lines, etc., have also been employed to inspect the resolution of SMLM reconstructed images \[69,70,88,138,277\]. In the following, it will be shown that Rayleigh’s two-points resolution criterion is related to localization precision in SMLM techniques and some selected image resolution metrics developed for SMLM techniques will be presented in more details.

Two-points resolution. Rayleigh’s resolution criterion was originally developed for observations with the human eye. It is defined as the ability of the eye to distinguish two closely spaced objects. In conventional microscopy, the resolving power of a lens is given by the smallest distance, \(d\), between two point-like emitters that can be distinguished under a microscope \[4\]. Rayleigh’s resolution criterion expresses that two noncoherent sources of light can be resolved when at least separated by a distance equal to the separation between the maximum and the first minimum of the diffraction pattern of one of the sources. The Rayleigh’s resolution distance for point sources is given by

\[
D = \frac{0.61 \lambda}{N_a} \tag{33}
\]

where \(\lambda\) and \(N_a\) are the wavelength of the light and the numerical aperture of the lens, in turn.

The diffraction of light from a circular aperture/lens is given by the Airy pattern \[4\]

\[
I(\theta) = I_0 \left[\frac{2J_1(2\pi n a \sin \theta)}{2\pi n a \sin \theta}\right]^2 \tag{34}
\]

where \(J_1, a, n, I_0, \lambda\) and \(\theta\) are, respectively, the Bessel function of the first kind of order one, the radius of the aperture/lens, refractive index of the medium, intensity, wavelength of light and the half angle of observation, Fig. 9. The first zero of this intensity pattern occurs at \(\frac{2\pi n a \sin \theta}{D} = 3.83\) which yields \(D = 0.61 \frac{\lambda}{N_a}\) where \(N_a = n \frac{D}{R}\) and \(\sin \theta = \frac{D}{R} \sim \frac{D}{f}\). \(D\) and \(f\) are, respectively, the distance between the main maximum with the first minimum of intensity in the Airy pattern and the focal distance of the lens.

The Rayleigh resolution, \(D\), is proportional to the size of the diffraction pattern/PSF, on the camera, \(D \propto \sigma_{PSF}\), in conventional microscopy. In super-resolution microscopy, an isolated emitter is represented by a blob with a size equal to the localization precision. Therefore the Rayleigh’s resolution in SMLM microscopy is related to the localization precision

\[
D \propto \frac{\sigma_{PSF}}{\sqrt{N}} \tag{35}
\]

which is better than resolution in conventional microscopy by an order of \(\sqrt{N}\), where \(N\) is the number of photons from the emitter.

Image resolution. While localization precision is a key parameter in evaluating the two-points resolution of super-resolution microscopy, it does not provide a comprehensive assessment of resolution for images of complex biological structures, reconstructed from millions of found emitter locations. Another essential metric to evaluate the resolution of SMLM images is the density of localizations. It describes how many localizations were observed within a unit of area of an image. The Nyquist-Shannon sampling theorem states that the minimum sampling frequency of a signal must be at least double of its highest frequency component in the inverse space to reconstruct the underlying structure with no distortion \[278,279\]. In the field of SMLM, the Nyquist-Shannon theorem can be interpreted that to obtain a desired resolution, the nearest neighbor distance between localized emitters should be at least half of the desired resolution \[280\]. However, it has been observed that
the real number of localizations required to accomplish such a resolution is higher than the minimum specified by the Nyquist-Shannon criterion due to the random nature of sampling with low precisions in SMLM procedures \[141, 281-283\].

\[ \Delta_l(k) \leq F^{-1}(k) \]  

Low localization density can be due to several problems in super-resolution microscopy, such as insufficient labeling, broken labels or filtering localizations in the thresholding stage because of inadequate fitting quality, etc. For some cases, such as experiments where there are multiple identical structures, this problem can be overcome by aligning and fusing the images of similar structures \[284-286\]. Several alignment and fusion algorithms have been reported in the literature, including a few that require a template or structural assumptions in the alignment step \[287-291\] as well as template-free particle fusion algorithms \[122, 292-294\].

ITF (information transfer function) formalism gives image resolution bounds by providing a minimum on precision for image frequency estimations

\[ \Delta_I(k) \leq F^{-1}(k) \]  

where \( \Delta_I, k \) and \( F \) stand for uncertainties, spatial frequency, and the Fourier transform of ITF, respectively. This idea of resolution equally applies to both conventional and stochastic microscopy and unifies the concept of resolution \[271\]. Although ITF provides a generalized concept of resolution, it requires models of the target structure which makes it limited in practice \[86\].

The FRC algorithm was adopted from electron microscopy \[295\] and adapted for resolution measurement in stochastic fluorescent microscopy \[65, 272\]. This approach uses two images from two identical structures or reconstruction of two images of the same structure by splitting the list of localizations into two halves. It then calculates the cross-correlations of the two images at different image frequencies, where components with frequency \( k \) are given by a ring with radius \( |k| \) in the Fourier domain. The larger frequencies represent finer details in the image. It is there the two images
start to deviate and hence their cross-correlation rapidly declines. The frequency at which the cross-correlation falls below a given threshold can be utilized to calculate the image resolution. The method takes into account both localization precision and labeling density. It however has to be used with care for structures with more complicated geometries and discontinuous boundaries [86,141].

SQUIRREL compares diffraction-limited images and super-resolution equivalents of the same acquisition to identify artifacts and disappearance of details in the reconstructed images [273]. SQUIRREL does not require any prior knowledge of the sample and is able to identify common super-resolution artifacts. However, out-of-focus light affects the performance of SQUIRREL and, moreover, it cannot recognize small-scale artifacts. This approach returns a quantitative map of image anomalies and artifacts rather than reporting a resolution measure. The returned map can be used to optimize the experiment and image analysis, and improve the reconstructed image qualities. SQUIRREL was used to show that high image resolution does not necessarily correlate with artifact-free reconstructions [273].

Resolution depends on multiple experimental and image analysis factors. A proper choice of labels, buffers, fixation protocols, and other experimental factors can lead to better localization uncertainties and less artifacts and therefore better image resolution. The choice of a localization algorithm also helps in optimizing both localization precision and localization density, reducing the image artifacts. The image rendering and visualization techniques also influence the image resolution. It has been demonstrated that different visualization procedures yield different resolutions for images reconstructed from the same list of emitter coordinates [296].

6 Applications of Single Molecule Localization Microscopy

Super-resolution microscopy has had significant contributions in shedding light on numerous biological problems since its advent in the 1990s. The major improvement in resolution of microscopy images helped with unraveling details of many biological structures and processes, such as nuclear pore complexes [270,293,297], actin structures [63], cell membrane [298,299], cell division [300], neurons [301,302], plant cell biology [303,304], live cell imaging [280,305,306], and many more [22,29,27,307].

In addition to visualization of intricate structures, a tremendous quantitative insight into cell biology can be gained through post-processing of resulting localizations from SMLM techniques. These post-processing algorithms include single particle tracking (SPT) [142,308,309], cluster analysis [310,311], molecule counting [312-320], particle fusion [122,284-293], etc. In the following, SPT and clustering approaches are described in more details.

6.1 Single Particle Tracking

While super-resolution microscopy only deals with spatial resolution, Single Particle Tracking (SPT) is concerned with spatial as well as temporal resolution of dynamic samples. The microscopic world of biology is a live and vibrant place where many phenomena and interactive processes take place over time. An effective examination of these types of processes and interactions requires a comprehensive knowledge of dynamics and the motion of particles in those environments.

SPT was first demonstrated by optical visualization of gold nano-particles on cell membranes [321,322], which paved the path for use of SPT in the study of cell membranes [323,324]. Since the first demonstration of SPT in cell biology, there have been a burst of research using SPT that have revolutionized our understanding of the cell membrane [325,328]. An example of such research is the use of SPT in shedding light on the confined motion of receptors on the cell membrane imposed by the actin cytoskeleton [326,329]. SPT has also been employed to explore intracellular environments, including influenza and HIV virus internalization [330,332], and cargo transport along microtubules [333].
SPT is comprised of three main steps: detection and localization, linking, and post processing. The detection and localization of probes in SPT is similar to emitter localization in SMLM techniques and most of the fitting approaches discussed before can be employed for this stage of SPT. As described previously, more photons from the probes lead to more precise localizations. On the other hand, to increase the temporal resolution, a higher frame rate is desired during data acquisition. Higher frame rate means shorter exposure time and less photons and hence larger localization uncertainties. Therefore, bright probes are necessary for both high temporal resolution and precise localizations. Other important elements are photo-stability and size of the probes \cite{334}. Probes with long-lasting photo-stability and small size are desired for obtaining longer trajectories and less perturbation in the mobility and dynamics of the particles under study. There are three major categories of probes used in SPT: nano-particles, organic dyes and quantum dots (QDs) \cite{309}. Nano-particles reflect light rather than emitting fluorescent light and have high photo-stability but their size is rather large compared to typical proteins. Organic dyes are very small compared to typical proteins but they are really dim and bleach rapidly \cite{309}. The size of QDs are in-between organic dyes and nano-particles. They are relatively bright and photo-stable, which make them a perfect probe for most SPT experiments. QDs are manufactured with different emission wavelengths and are also suitable for multi-color SPT \cite{335,337}.

After detection and localization, the detected probes are linked together across consecutive frames to construct particle trajectories. Linking is a non-trivial problem, even in the presence of only a few probes, Fig. 1.13. This is also the case where there is an equal number of probes in every given frame, in the absence of blinking, bleaching, probes entering or leaving the field of view, and missed probes in the detection stage. The reported linking algorithms in SPT can be categorized in two classes: deterministic and probabilistic approaches. Deterministic approaches give the same results every time, but probabilistic procedures use a random number generator at some point in the analysis and depending in the sequence of random numbers produced, they give slightly different answers each time. Recently, deep learning approaches have also been employed to implement SPT \cite{338,341}.

Given a set of localizations, deterministic approaches construct trajectories by linking the localizations so that the resulting trajectories minimize a certain cost function \cite{342}. The reported cost functions include distance \cite{343,347} as well as concepts such as minimal energy path \cite{348,350} or inertia \cite{351} borrowed from classical mechanics, and ad hoc cost functions that can be a function of parameters like probe location, intensity, motion direction, etc. \cite{352,355}. A range of different optimization algorithms have been employed to minimize the aforementioned cost functions, including the Hungarian algorithm \cite{346,353,356} and the greedy algorithm \cite{351,352,355}.

Probabilistic SPT approaches make use of a Bayesian algorithm to obtain the most probable tracks in the linking problem. SPT algorithms that implement a Bayesian procedure have demonstrated better performances compared to deterministic approaches due to inclusion of prior information \cite{357}. Assume a system with state \( x_t \) at time \( t \), which leads to an observation \( z_t \), where \( x_t \neq z_t \) due to noise. The state at time \( t \) is a function of the state at time \( t-1 \) and noise as follows

\[
x_t = f_t(x_{t-1}, u_t)
\]  

(37)
where $f_t$ and $u_t$ are, respectively, a function that characterizes the system and a variance. The observation also deviates from the state of the system due to noise and is given by

$$z_t = g(x_t, v_t)$$  \hspace{1cm} (38)

where $v_t$ is the noise variance. The objective is finding the state of the system at time $t$, $x_t$, given the list of observations up to this time, $z_{1:t}$. Using Bayes theorem, it can be shown that

$$P(x_t|z_{1:t}) = \frac{P(z_t|x_t)P(x_t|z_{1:t-1})}{P(z_t|z_{1:t-1})}$$  \hspace{1cm} (39)

where $P(z_t|x_t)$ is the likelihood, and the prior is given by

$$P(x_t|z_{1:t-1}) = \int P(x_t|x_{t-1})P(x_{t-1}|z_{1:t-1})dx_{t-1}$$  \hspace{1cm} (40)

Equations (39) and (40) provide a recursive formula to obtain the current state of the system from the list of observations up to this time along with the previous state of the system. However, the form of the posterior as a function is still unknown. One approach takes $P$ to be a Gaussian function, which is called the Kalman filter [359, 365]. The Kalman filter describes a linear system characterized by a linear function $f_t$ and Gaussian noise $g$. For example, diffusion is a linear process and can be characterized by a Kalman filter. Another common filter is the particle filter [115, 358, 366, 370]. This filter is suitable for non-linear processes with non-Gaussian noise. For particle filters, a Monte Carlo procedure is often utilized to take some samples from the system, which are then used to compute the posterior probabilities. Other filters such as the Gaussian Mixture Probability Hypothesis Density (GM-PHD) filter, Bayesian random set filter, etc. have been employed for probe linking purpose [371, 373].

Biological samples usually exhibit a combination of different motion types such as Brownian motion, directed motion, confined motion, etc. Interacting Multiple Models (IMM) allows modeling the kinetics of the probes as a combination of different motions employing different filters [374, 377]. The IMM filter is usually implemented employing a Bayesian approach where a weight is associated with each filter and the algorithm switches between models by updating the weights.
The recursive method described above provides an approach that links new probes to the trajectories on a frame by frame basis. The Multiple Hypothesis Tracking (MHT) algorithm evaluates the possibility of different tracks taking into account localized probes over either the entire data set or over a time window \[378-383\]. While this procedure accomplishes the most optimal solution to the linking problem, it is computationally extremely expensive and impractical. Greedy algorithms accomplish approximations to the MHT optimal solution with tremendously less computational cost \[380-384\].

Jaqaman et al. \[380\] proposed a relatively computationally inexpensive approximation to MHT using a greedy algorithm. This procedure uses a cost matrix approach to incorporate appearance (birth) and disappearance (death) of the probes in the model. They introduced ghost probes to consider three different linking scenarios when there is not an equal number of detected probes in consecutive frames, Fig. 11. The real probes are connected together using a cost calculated from the localization precisions and kinetics of the probes.

\[ P(x_2,t_2|x_1,t_1) = \mathcal{N}(x_1,x_2,\sigma^2) \] (41)

where \( x \) stands for the probe locations and \( \sigma^2 \) is the variance due to diffusion and localization precisions, \( \sigma_x \), defined as

\[ \sigma^2 = 2D\Delta t + \sum_{i=1}^{2} \sigma_{x_i}^2 \] (42)

where \( D \) and \( \Delta t \) are the diffusion constant and exposure time, in turn. A real probe can be connected to a ghost probe when a probe goes either off or on and the penalty is computed from the blinking statistics of the probes. The blinking process is assumed to be memoryless with \( k_{on} \) and \( k_{off} \) being the rate of probes, respectively, going from off to on or on to off.

\[
\begin{align*}
P(\text{off} \rightarrow \text{on}|k_{on}, \Delta t) &= k_{on}\Delta t \\
P(\text{on} \rightarrow \text{off}|k_{off}, \Delta t) &= k_{off}\Delta t
\end{align*}
\] (43)

Additionally, the probabilities for a probe staying on or off for \( N \) frames is given as

\[
\begin{align*}
P(\text{Stay off}|N\Delta t) &= P(\text{Not going on}|N\Delta t) = (1 - k_{on}\Delta t)^N \\
P(\text{Stay on}|N\Delta t) &= P(\text{Not going off}|N\Delta t) = (1 - k_{off}\Delta t)^N
\end{align*}
\] (44)

Eventually, ghost probes can also be linked together where the costs are given by the transpose cost matrix of the real probes. The Hungarian procedure is utilized to find the connections with the least cost.

The first stage only connects probes across consecutive frames and produces short trajectories, Fig. 11. In a second stage, the resulting short trajectories are connected together to obtain probe trajectories across the entire given sequence of the frames, which is called gap-closing. The gap-closing cost function is also a function of blinking statistics and localization precisions, except this time the probes are allowed to be linked together in non-consecutive frames.
Once the trajectories are constructed, they can be employed to extract information about the underlying dynamics of the biological sample under study \[308, 309, 385, 386\]. Mean Square Displacement (MSD) is the most common post-analysis of trajectories employed for this purpose. It is defined as the average of spatial distances between all pairs of localizations that are temporally separated by certain times, called the time lag. Given a trajectory comprised of \(N\) localizations, the MSD can be calculated as follows:

\[
\text{MSD}(t_{\text{lag}} = m\Delta t) = \frac{1}{N - m} \sum_{i=1}^{N-m} [x(t_i + m\Delta t) - x(t_i)]^2
\]

(45)

where \(x(t_i)\) is the location of the probe at time \(t_i\) and \(x(t_i + m\Delta t)\) is the probe location at \(t_{\text{lag}} = m\Delta t\) later. The MSD is a function of the time lag, \(t_{\text{lag}}\), and this function is extensively investigated and well characterized for different motion types. By comparing the resulting MSD function from the obtained trajectories and the theoretical MSD forms, one is able to determine the underlying dynamic of the system under study. For diffusion or Brownian motion, the MSD is proportional to the time lag

\[
\text{MSD}(t_{\text{lag}}) = 2dD t_{\text{lag}}
\]

(46)

where \(d\) is the spatial dimensionality of the motion.

### 6.2 Clustering

Clustering is the task of classifying a given set of data points into subsets in such a way that data points in a subset are more similar to each other than those in other subsets, based on a given property \[387\]. Clustering has been employed in many scientific spheres, including localization microscopy, recognizing patterns, detecting communities, etc. There are different levels of clustering in a list of localizations resulting from a SMLM experiment \[310, 311\]. In SMLM techniques, there are multiple observed localizations from an emitter over the course of data acquisition that form a cluster, which we will call here an intra-cluster. A higher level of clustering is clustering between emitters/molecules that signifies interactions between the molecules in a cluster at the biological

---

**Figure 11:** An instance of probe linking in two consecutive frames in the presence of ghost probes. The blank and filled circles represent ghost and real probes.
level. We call this type of cluster inter-clusters. There is also co-clustering that takes place among
different types of molecules imaged via multi-color super-resolution microscopy \[388–391\].

Multiple algorithms have been developed or adapted to identify all sorts of clusters within SMLM
localizations, including algorithms that inspect the extent of clustering within a data set \[392\] \[398\] \[404–406\]. These approaches have been popular in post-processing of SMLM results of cell membrane
samples, where it is conjectured that molecular clusters indicate underlying membrane structure or
cell signaling \[407–412\].

Some methods examine the degree of grouping or group properties of clusters, such as the shape or
average density within a data set, Fig. 12. A few of these approaches are nearest neighbor distances
(NND) \[392\], Hopkins statistics \[393\], and Ripley’s function and pair correlation \[394–397\]. The
NND probability distribution for uniform randomly distributed data is given by

\[ f(r) = 2 \pi \rho r e^{-\pi \rho r^2} \]  

where \( \rho \) is the density of the data points. The deviation of the NND distribution for a given data set
from \[47\] indicates either clustering or a more regularly spaced data set, Fig. 12. Hopkins statistics
\((H)\) tests for spatial randomness of a point pattern by comparing nearest neighbor distances between
a given data set and a uniform randomly distributed data set. Values of \( H \) near 0.5 imply randomly
distributed data, while values near 1 indicate highly clustered data, and values near zero signify
more regularly spaced data, Fig 12.

The Ripley’s K-function, \( K(r) \), is another statistical test that explores the extent of clustering
within a given data set. Defining \( k_i(r) \) as the number of points within distance \( r \) from the \( i \)th point,
\( K(r) \) is given by the average of the \( k_i \) for all data points divided by the mean density over all data
points. The clustering behavior of the given data set is then given by

\[ K(r) < \pi r^2 \quad \text{regularly spaced} \]
\[ K(r) = \pi r^2 \quad \text{random} \]
\[ K(r) > \pi r^2 \quad \text{clustered} \]  

Pair correlation analysis is the same idea as Ripley’s K-function extended to images via pixels rather
than a set of points.

A range of clustering algorithms have been developed that take advantage of density fluctuations
within a data set to identify clusters. DBSCAN and Voronoi tessellation algorithms are among the
most popular density based approaches in SMLM data post-analysis. DBSCAN has two inputs. One
of them is the maximum distance between the points within a cluster and the other is the minimum
number of data points within a cluster. The algorithm starts from a random point and adds points
to the set until there is no more points within the given maximum distance. If the number of
points inside the set is more than the given threshold it will be returned as a cluster, otherwise it is
considered as outlier. Voronoi tessellation draws boundary line segments between every pair of data
points in the given data set so that the distance from every member of a pair to the line between
them is equal. The final geometry is comprised of polygons where each polygon contains only one
data point, called a Voronoi diagram. This algorithm identifies clusters by inspecting the number of
vertices and the area of the polygons at different neighboring levels.
Bayesian clustering algorithms for SMLM data are superior to density based approaches because they take advantage of prior knowledge. Available prior information can be included in Bayesian algorithms via prior distributions. Rubin-Delanchy, et al. developed an algorithm to identify inter-clusters within SMLM localizations, called Bayesian cluster identification [310,404]. This algorithm classifies the localizations into either background or signal by means of a binomial distribution. A large number of clustering proposals are then put forward using a procedure similar to Ripley’s K-function. Scores for different clustering proposals are calculated using the posterior where the Dirichlet distribution is the prior on different arrangements. At the end, the configuration with the highest score is returned as the solution.

Post, et al. proposed a Bayesian clustering algorithm to identify intra-clusters (emitters) on the surface of spherical nano-particles [405]. Their algorithm takes full advantage of localization precisions but it does not return the number of emitters on the surface of every individual nanoparticle. Otherwise, they find the mean number of emitters on the surface of nano-particles by fitting a log-normal distribution to the number of localizations per nano-particle. They next employ this piece of information to localize those emitters and then inspect their inter-clustering behavior using the NND distribution.

Fazel et al. developed a Bayesian Grouping of Localizations (BaGoL) that takes advantage of localization precisions as well as mean number of blinking/binding events per emitter to identify and localize emitters with sub-nanometer precision in dense regions [406]. This algorithm uses nearest neighbor distributions and an intensity filter to recognize and remove the outliers.

Lin, et al. developed a non-Bayesian clustering algorithm based on a hierarchical clustering paradigm, which allows exploitation of localization precisions [410]. This algorithm proposes different clustering configurations for a given set of localizations similar to the hierarchical procedure and then performs a hypothesis test to pick one of the proposed clustering models.

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